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O. Anderson, H. Kellerer; A. Linder, H. Münzner, S. Sagoroff, W. Winkler

Editors
Prof. Dr. W. Uhlmann, Institut für Angewandte Mathematik und Statistik, Universität Würzburg, Sanderring 2, D-8700 Würzburg
Prof. Dr. O. Krafft, Institut für Statistik und Wirtschaftsmathematik, Rheinisch-Westfälische Technische Hochschule Aachen, Wüllnerstraße 3, D-5100 Aachen

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